

Amendments to the specification:

Kindly replace the title of the invention wherever it appears in the application and supporting documents with the following revised title:

**METHOD AND SYSTEM FOR TESTING MULTI-CHIP INTEGRATED
CIRCUIT MODULES**

Amendments to the specification:

Kindly replace the abstract of the disclosure with the following revised abstract:

ABSTRACT OF THE DISCLOSURE

A system and method for utilizing a multi-probe tester to test an electrical device having a plurality of contact pads. Multi-probe tester test probes and electrical device contact pads are arrayed in a common distribution pitch, ~~and a means for masking test probes masks wherein at least one test probe is masked~~, thereby preventing the at least one test probe from returning a test result to the testing apparatus. In one embodiment ~~the means for masking test probes is a mask membrane physically preventing prevents~~ at least one test probe from making contact with the electrical device. In another embodiment, ~~the means for masking is~~ at least one software command is provided configured to cause an input from at least one test probe to be disregarded during a test routine. Another embodiment features both mask membrane and software command probe masking.